

Modified Form PTO/SB/08A

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)	<i>Complete If Known</i>	
	Application Number	09/527,931
	First Named Inventor	Gaetan L. Mathieu
	Filing Date	March 17, 2000
	Group Art Unit	3726
	Examiner Name	Chang, Rick Kiltac
No. of Refs.: 4	Attorney Docket No.	P114-US

FOREIGN PATENT DOCUMENTS								
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Office <sup>2</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup>	Name of Patentee or Applicant	Publ. Date	T <sup>6</sup>	Copy Enclosed
	1.	JP	10-031034		Amamiya	2/1998		Yes

OTHER PRIOR ART – NONPATENT LITERATURE DOCUMENTS								
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published					T <sup>2</sup>	Copy Enclosed
	2.	United States District Court, Northern District of California, San Francisco Division, Case No. 3:06-CV-07159 JSW, Defendants' Patent Local Rule 3-3 Preliminary Invalidity Contentions for U.S. Patent Nos. 6,246,247, 6,509,751, 6,624,648, and 7,073,254, October 8, 2007						Yes
	3.	United States International Trade Commission, In the Matter of Certain Probe Card Assemblies, Components Thereof and Certain Tested DRAM and NAND Flash Memory Devices and Products Containing Same, Inv. No. 337-TA-621, Respondent Micronics Japan Co., LTD's First Supplemental Response to Complainant FormFactor, Inc.'s First Set of Interrogatories (Nos. 25-29), Exhibit 5, March 14, 2008.						Yes
	4.	United States International Trade Commission, In the Matter of Certain Probe Card Assemblies, Components Thereof and Certain Tested DRAM and NAND Flash Memory Devices and Products Containing Same, Investigation No. 337-TA-621, Supplemental Response of Phicom Corporation to Complainant FormFactor, Inc.'s First Set of Interrogatories (Nos. 26-30), Exhibit 29, March 14, 2008.						Yes

Examiner Signature	Date Considered
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\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

\*\* Reference cited in parent application US Serial No. \_\_\_\_\_, CFR § 1.98(d)

\*\*\* Pre-OG Notice By Deputy Commissioner Stephen G. Kunin dated July 11, 2003 waiving the requirement to file copies of US patent publications in applications filed after June 30, 2003.

& Notice dated October 19, 2004 by Deputy Commissioner for Patent Examination Policy waiving requirement to file copies of pending US patent applications if the applications are stored in the USPTO's IFW system.

# Commonly owned US patent or application whose subject matter may be related to the subject matter of the instance patent application.